

Inventor: Garo J. Derderian et al.

Title: Atomic Layer Deposition Method of Forming an Oxide Comprising Layer on a Substrate

Assignee: Micron Technology, Inc.

INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56. Pursuant to 1276 OG 55, August 5, 2003, no copies of cited U.S. patents or U.S. patent application publications are included, as the date of filing of this patent application occurs after June 30, 2003. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 2-19-04

Attorney: 

Mark S. Matkin
Reg. No. 32,268

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| Form PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. MI22-2403 | | SERIAL NO. Unknown | |
| LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT: Garo J. Derderian et al. | | | |
| | | | | FILING DATE February 19, 2004 | | GROUP Unknown | |

| U.S. PATENT DOCUMENTS | | | | | | | |
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| *Examiner's Initials | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | |
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